



IFW

03560.003445.

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	)	
	:	Examiner: Not Yet Assigned
TADAO ENDO	)	
	:	Group Art Unit: 2878
Application No.: 10/829,257	)	
	:	
Filed: April 22, 2004	)	
	:	
For: RADIATION IMAGING	)	
APPARATUS, RADIATION	:	
IMAGING SYSTEM, AND	)	
RADIATION IMAGING	:	
METHOD	)	August 23, 2004

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed foreign documents are also enclosed.

The concise explanation of relevance for the non-English documents is provided in the English abstracts attached to those documents.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicant's undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

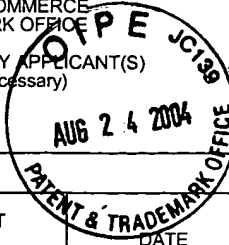
Respectfully submitted,

A handwritten signature in dark ink, appearing to read 'Fritz Klantschi', is written over a horizontal line.

Fritz Klantschi  
Attorney for Applicant  
Registration No.: 50,333

FITZPATRICK, CELLA, HARPER & SCINTO  
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NYMAIN447687

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. <b>03560.003445</b>		APPLICATION NO. <b>10/829,257</b>	
				APPLICANT <b>TADAO ENDO</b>			
				FILING DATE <b>April 22, 2004</b>		GROUP <b>2878</b>	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	JP	2000-116637	04/25/00	Japan	A61B	6/00	Abstract
	JP	5-260382	10/08/93	Japan	H04N	5/325	Abstract
	JP	2-273873	11/08/90	Japan	G06F	15/62	Abstract
	JP	3-133276	06/06/91	Japan	H04N	5/325	Abstract
	JP	3-106343	05/02/91	Japan	A61B	6/00	Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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